



**Micropolis Convention Center
Besançon (France)
9-13 July 2017**



First Call for Papers - Abstract Submission Deadline: March 3, 2017

The IFCS and EFTF have chosen the Micropolis Convention Center in Besançon (France) as the 2017 venue for our continuing biennial joint conference. Besançon is the historical landmark of EFTF and is only 2h30 from Paris by TGV high-speed train. The Micropolis Convention Center is connected to Besançon downtown by modern tramway.

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Abstracts will be collected through a web-based submission tool. For details on abstract submission and conference information, please go to www.eftf-ifcs2017.org

Authors are invited to submit abstracts of recent and original work of interest to the frequency control communities in the following topics:

Group 1: Materials, Resonators & Resonator Circuits

- A. Fundamental Properties of Materials
- B. Micro and Meso-scale-Fabrication Technology for Resonators and Filters
- C. Theory, Design and Performance of Resonators and Filters, including BAW, FBAR, MEMS, NEMS, SAW, and Novel Devices
- D. Reconfigurable Frequency Control Circuits, e.g. Arrays, Channelizers

Group 2: Oscillators, Synthesizers, Noise, & Circuit Techniques

- A. Oscillators, BAW, SAW, MEMS, Microwave & Optical
- B. Integrated Oscillators
- C. Synthesizers, Optical to Microwave and RF Conversion with Combs
- D. Noise, Ageing and Measurements
- E. Analog and Digital Electronics and Signal Processing

Group 3: Microwave Frequency Standards & Applications

- A. Microwave Atomic Frequency Standards
- B. Atomic Clocks for Space Applications
- C. Vapor-cell Atomic Clocks and cell-based Sensors and Instruments
- D. Atomic Interferometers
- E. Fundamental Physics Tests with Clocks and Other Applications

Group 4: Sensors & Transducers

- A. Resonant Chemical Sensors
- B. Resonant Physical Sensors
- C. Vibratory Gyroscopes and Magnetometers
- D. BAW, SAW, FBAR and MEMS Sensors
- E. Transducers
- F. Sensor Instrumentation

Group 5: Timekeeping, Time and Frequency Transfer, GNSS Applications

- A. TAI and Time Scales, and associated Algorithms
- B. GNSS and related timing applications
- C. Telecommunications Network Synchronization
- D. Time and Frequency Transfer
- E. Frequency and Time Distribution
- F. Frequency and Time Calibration Services

Group 6: Optical Frequency Standards and Applications

- A. Optical Ion and Neutral Atom Clocks
- B. Optical Frequency Combs and Frequency Measurements
- C. Ultra-stable Laser Sources and Optical Frequency References
- D. Ultra-stable Frequency Transfer between Optical, Microwave, TeraHertz, and XUV Domains
- E. Fundamental Physics Tests with Accurate Optical Spectroscopy, Other Applications

MORE INFO TO COME AT eftf-ifcs2017.org